SYSTEM AND METHOD FOR ERASE TEST OF INTEGRATED CIRCUIT DEVICE HAVING NON-HOMOGENEOUSLY SIZED SECTORS

ABSTRACT OF THE DISCLOSURE

A system and method for testing a flash memory device having uniform sectors and smaller, "boot" sectors includes determining uniform and boot test limits based on average erase and APDE time periods of the uniform and boot sectors, respectively. In this way, the erase test results for each sector type is compared against test limits that are based only on that sector type, thereby avoiding excessive false rejects.

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